



European space research
and technology centre

Components Division
Laboratory Support Group

RADIATION ANALYSIS REPORT

RA 064

Part Type : Integrated Circuit
High Speed CMOS

Type No : M54HC86F1

Manufacturer: SGS

Project : Standardisation

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Summary

1. A large increase in Quiescent Device Current occurred for those devices irradiated with bias applied.
2. A change from positive to negative voltage was measured for P-Channel Threshold voltage for those devices irradiated with bias applied.
3. There were no significant changes for the remaining DC and AC parameters.



1.0 Introduction

This assessment of radiation performance, of the M54HC86 manufactured by SGS, was undertaken to establish whether any changes in radiation susceptibility had occurred due to the transfer of the wafer fabrication to a different manufacturing plant.

2.0 Objective

The objective of the test was to establish that the devices assembled from wafers processed at the new plant had the same radiation performance as previously evaluated for the original wafer fabrication location.

The device type tested was supplied by SGS on a random basis and was not specifically identified by ESTEC as necessarily being 100% representative of the new wafer processing plant.

3.0 Radiation Source and Dosimetry

The 1460 Curie Co-60 facility at ESTEC was used for exposing the samples to ionising radiation (1.25 MeV gamma radiation). The dose rate can be varied by placing the samples at a different distance from the Co-60 pellets. The dose rate chosen for the irradiation in this test is detailed in paragraph 4.0.

The dose was monitored using an Ionex Dosemaster equipped with a 0.6cc ion probe placed at the same distance from the Co-60 source as the samples. The Ionex Dosemaster is calibrated to $\pm 0.5\%$.

4.0 Sample Identification and Allocation

A total of 10 parts were available and were distributed as follows:-

Note:- 2 parts were not subjected to irradiation and were kept as control samples.

Sample	Condition	Description
21	A	Static
22	A	Static
23	A	Static
24	A	Static
32	B	Static
H7	B	Static
H8	B	Static
H9	B	Static
73	-	Control
74	-	Control

A. Figure 1

B. All pins grounded



5.0 Biasing Conditions

The biasing conditions applied, during the irradiation of the devices, are shown in figure 1.

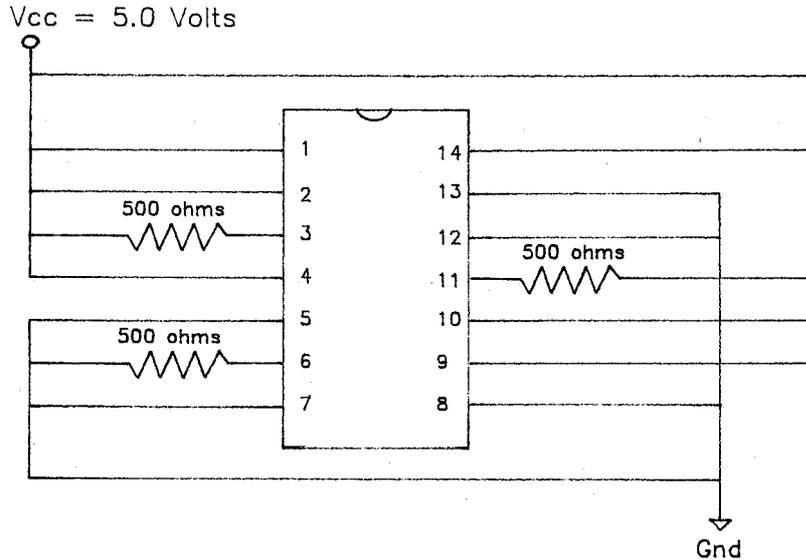


Figure 1 Biasing circuitry

6.0 Irradiation Schedule

The following information details the time and dose rate schedule used in the performance of this radiation testing:-

Start Time	Accumulated Dose (krad)	Dose Rate (rads/min)
08:57	6.0	147.1
10:02	10.0	146.5
10:59	15.0	146.5
13:26	25.0	146.5
15.45	40.0	146.5

Note:- The irradiation was carried out on 20.03.91.

7.0 Test Results

A very large quantity of test data was generated during this analysis, for the purposes of presentation in this report the DC results of one device from each group only is included. The test results for Quiescent Device Current for group A, and P-Channel Threshold Voltage of one device from each group are presented graphically in figures 2-4 as these are the only parameters that vary significantly.

Input Clamp Voltage

Device Number 21 (Irradiated with bias)

Pin Identity	VIKN		LIMIT		400 mV <--> 900 mV		CURRENT 100 μ A		ABSOLUTE LEVELS	
	0Krad	6Krad	10Krad	15Krad	25Krad	40Krad	40Krad	40Krad	40Krad	Annealed
A1	-634 mV	-637 mV	-634 mV	-633 mV	-638 mV	-637 mV	-638 mV	-637 mV	-633 mV	-633 mV
A2	-634 mV	-636 mV	-634 mV	-633 mV	-637 mV	-635 mV	-637 mV	-635 mV	-633 mV	-633 mV
A3	-634 mV	-636 mV	-634 mV	-634 mV	-637 mV	-636 mV	-637 mV	-636 mV	-632 mV	-632 mV
A4	-635 mV	-636 mV	-636 mV	-635 mV	-639 mV	-638 mV	-638 mV	-638 mV	-634 mV	-634 mV
B1	-635 mV	-636 mV	-635 mV	-633 mV	-638 mV	-636 mV	-638 mV	-636 mV	-634 mV	-634 mV
B2	-635 mV	-636 mV	-636 mV	-634 mV	-639 mV	-638 mV	-639 mV	-638 mV	-633 mV	-633 mV
B3	-633 mV	-635 mV	-634 mV	-633 mV	-637 mV	-635 mV	-637 mV	-635 mV	-632 mV	-632 mV
B4	-634 mV	-637 mV	-635 mV	-634 mV	-638 mV	-637 mV	-638 mV	-637 mV	-634 mV	-634 mV

VIKP LIMIT 400 mV <--> 900 mV
CURRENT 100 μ A
ABSOLUTE LEVELS

Pin Identity	VIKP	LIMIT	400 mV	900 mV	ABSOLUTE LEVELS
A1	666 mV	668 mV	667 mV	663 mV	666 mV
A2	663 mV	668 mV	667 mV	665 mV	665 mV
A3	672 mV	666 mV	672 mV	665 mV	662 mV
A4	666 mV	663 mV	667 mV	663 mV	656 mV
B1	666 mV	666 mV	672 mV	667 mV	665 mV
B2	668 mV	674 mV	665 mV	662 mV	659 mV
B3	668 mV	672 mV	668 mV	666 mV	663 mV
B4	663 mV	667 mV	666 mV	663 mV	662 mV

Input Clamp Voltage

Device Number 32 (Irradiated with all pins grounded)

Pin Identity	VIKN LIMIT				CURRENT				ABSOLUTE LEVELS			
	0Krad	6Krad	10Krad	15Krad	400 mV	<-->	900 mV	100 μ A	25Krad	40Krad	25Krad	40Krad
A1	-637 mV	-637 mV	-638 mV	-637 mV	-638 mV	-637 mV	-637 mV	-637 mV	-638 mV	-638 mV	-638 mV	-638 mV
A2	-637 mV	-637 mV	-639 mV	-637 mV	-639 mV	-637 mV	-637 mV	-637 mV	-638 mV	-638 mV	-638 mV	-639 mV
A3	-637 mV	-636 mV	-639 mV	-637 mV	-639 mV	-637 mV	-637 mV	-637 mV	-638 mV	-638 mV	-638 mV	-638 mV
A4	-637 mV	-638 mV	-640 mV	-638 mV	-640 mV	-638 mV	-638 mV	-638 mV	-638 mV	-638 mV	-639 mV	-639 mV
B1	-638 mV	-637 mV	-640 mV	-639 mV	-640 mV	-639 mV	-639 mV	-639 mV	-638 mV	-638 mV	-638 mV	-638 mV
B2	-637 mV	-637 mV	-641 mV	-638 mV	-641 mV	-638 mV	-638 mV	-638 mV	-639 mV	-638 mV	-638 mV	-638 mV
B3	-637 mV	-636 mV	-638 mV	-636 mV	-638 mV	-636 mV	-636 mV	-636 mV	-637 mV	-637 mV	-638 mV	-638 mV
B4	-638 mV	-637 mV	-640 mV	-638 mV	-640 mV	-638 mV	-638 mV	-638 mV	-638 mV	-638 mV	-639 mV	-639 mV

Pin Identity	VIKP LIMIT				CURRENT				ABSOLUTE LEVELS			
	0Krad	6Krad	10Krad	15Krad	400 mV	<-->	900 mV	100 μ A	25Krad	40Krad	25Krad	40Krad
A1	674 mV	672 mV	674 mV	667 mV	674 mV	667 mV	667 mV	667 mV	663 mV	663 mV	662 mV	662 mV
A2	668 mV	663 mV	667 mV	668 mV	667 mV	668 mV	668 mV	668 mV	668 mV	668 mV	659 mV	659 mV
A3	670 mV	667 mV	674 mV	668 mV	674 mV	668 mV	668 mV	668 mV	662 mV	662 mV	665 mV	665 mV
A4	666 mV	668 mV	668 mV	668 mV	668 mV	668 mV	668 mV	668 mV	663 mV	663 mV	659 mV	659 mV
B1	668 mV	672 mV	668 mV	667 mV	668 mV	667 mV	667 mV	667 mV	668 mV	668 mV	665 mV	665 mV
B2	670 mV	667 mV	666 mV	666 mV	666 mV	666 mV	666 mV	666 mV	662 mV	662 mV	663 mV	663 mV
B3	668 mV	666 mV	670 mV	668 mV	670 mV	668 mV	668 mV	668 mV	666 mV	666 mV	666 mV	666 mV
B4	668 mV	666 mV	666 mV	668 mV	666 mV	668 mV	668 mV	668 mV	663 mV	663 mV	663 mV	663 mV

Input Clamp Voltage

Device Number 73 (Control-not irradiated)

Pin Identity	CURRENT 100 μ A				ABSOLUTE LEVELS				
	VIKN	LIMIT	400 mV	<--> 900 mV	6Krad	10Krad	15Krad	25Krad	40Krad
A1	-636 mV	-641 mV	-636 mV	-637 mV	-636 mV	-641 mV	-636 mV	-637 mV	-633 mV
A2	-635 mV	-641 mV	-636 mV	-636 mV	-636 mV	-641 mV	-636 mV	-636 mV	-633 mV
A3	-637 mV	-641 mV	-636 mV	-636 mV	-636 mV	-641 mV	-636 mV	-636 mV	-633 mV
A4	-636 mV	-641 mV	-636 mV	-637 mV	-636 mV	-641 mV	-636 mV	-637 mV	-632 mV
B1	-637 mV	-641 mV	-635 mV	-636 mV	-635 mV	-641 mV	-635 mV	-637 mV	-633 mV
B2	-637 mV	-641 mV	-636 mV	-636 mV	-636 mV	-641 mV	-636 mV	-637 mV	-633 mV
B3	-636 mV	-640 mV	-635 mV	-636 mV	-635 mV	-640 mV	-635 mV	-637 mV	-632 mV
B4	-636 mV	-641 mV	-636 mV	-637 mV	-636 mV	-641 mV	-636 mV	-637 mV	-632 mV

Pin Identity	CURRENT 100				ABSOLUTE LEVELS				
	VIKP	LIMIT	400 mV	<--> 900 mV	6Krad	10Krad	15Krad	25Krad	40Krad
A1	668 mV	677 mV	676 mV	668 mV	668 mV	677 mV	668 mV	668 mV	668 mV
A2	668 mV	668 mV	670 mV	668 mV	668 mV	668 mV	668 mV	668 mV	668 mV
A3	668 mV	670 mV	674 mV	668 mV	668 mV	670 mV	666 mV	667 mV	667 mV
A4	668 mV	670 mV	667 mV	672 mV	667 mV	670 mV	666 mV	674 mV	674 mV
B1	670 mV	670 mV	676 mV	670 mV	670 mV	670 mV	667 mV	676 mV	676 mV
B2	674 mV	670 mV	670 mV	674 mV	674 mV	670 mV	667 mV	668 mV	668 mV
B3	668 mV	672 mV	674 mV	667 mV	667 mV	672 mV	667 mV	670 mV	670 mV
B4	674 mV	670 mV	668 mV	674 mV	668 mV	670 mV	667 mV	667 mV	667 mV

Input Leakage Current

V_{cc} : 6.0V
 I_{ILL} : Pin under test-low, all other inputs grounded
 I_{ILH} : Pin under test-low, all other inputs at V_{cc}
 I_{IHL} : Pin under test-high, all other inputs grounded
 I_{IHH} : Pin under test-high, all other inputs at V_{cc}

Device Number 21 (Irradiated with bias)

Pin Identity	I_{ILL}					40Krad Annealed
	0Krad	6Krad	10Krad	15Krad	25Krad	
A1	150 pA	200 pA	400 pA	200 pA	-400 pA	150 pA
A2	-400 pA	-200 pA	0.00 A	0.00 A	350 pA	250 pA
A3	100 pA	250 pA	-150 pA	-300 pA	0.00 A	50.0pA
A4	150 pA	0.00 A	50.0pA	0.00 A	0.00 A	0.00 A
B1	-100 pA	-950 pA	-300 pA	0.00 A	0.00 A	0.00 A
B2	100 pA	250 pA	50.0pA	50.0pA	400 pA	600 pA
B3	0.00 A	-850 pA	0.00 A	-350 pA	-100 pA	-450 pA
B4	0.00 A	200 pA	-100 pA	50.0pA	0.00 A	0.00 A
Pin Identity	I_{ILH}					40Krad Annealed
	0Krad	6Krad	10Krad	15Krad	25Krad	
A1	350 pA	0.00 A	-850 pA	100 pA	200 pA	-400 pA
A2	350 pA	0.00 A	50.0pA	-600 pA	-500 pA	0.00 A
A3	0.00 A	-100 pA	0.00 A	200 pA	50.0pA	-100 pA
A4	0.00 A	-400 pA	-400 pA	-300 pA	-150 pA	0.00 A
B1	350 pA	0.00 A	0.00 A	200 pA	-500 pA	50.0pA
B2	0.00 A	-300 pA	-600 pA	0.00 A	450 pA	-450 pA
B3	0.00 A	-50.0pA	-200 pA	-200 pA	400 pA	0.00 A
B4	0.00 A	0.00 A	700 pA	400 pA	0.00 A	-400 pA

Input Leakage Current

Device Number 32 (Irradiated with all pins grounded)

I_{ILH}

Pin Identity	0Krad	6Krad	10Krad	15Krad	25Krad	40Krad
A1	500 pA	0.00 A	200 pA	200 pA	250 pA	0.00 A
A2	0.00 A	150 pA	0.00 A	0.00 A	0.00 A	50.0pA
A3	0.00 A	-300 pA	50.0pA	50.0pA	250 pA	550 pA
A4	500 pA	200 pA	100 pA	100 pA	0.00 A	200 pA
B1	0.00 A	600 pA	0.00 A	0.00 A	50.0pA	-200 pA
B2	0.00 A	0.00 A	500 pA	500 pA	0.00 A	600 pA
B3	-550 pA	0.00 A	-800 pA	-800 pA	0.00 A	200 pA
B4	400 pA	0.00 A	250 pA	250 pA	150 pA	-400 pA

I_{ILH}

A1	100 pA	350 pA	-750 pA	-750 pA	-200 pA	50.0pA
A2	-50.0pA	-750 pA	150 pA	150 pA	-300 pA	350 pA
A3	0.00 A	350 pA	50.0pA	50.0pA	50.0pA	100 pA
A4	400 pA	0.00 A	0.00 A	0.00 A	200 pA	250 pA
B1	600 pA	250 pA	100 pA	100 pA	50.0pA	0.00 A
B2	-250 pA	150 pA	-400 pA	-400 pA	200 pA	-200 pA
B3	50.0pA	-600 pA	0.00 A	0.00 A	-100 pA	0.00 A
B4	-250 pA	-50.0pA	-700 pA	-700 pA	150 pA	150 pA

Input Leakage Current

Device Number 73 (Control-not irradiated)

I_{in}

Pin Identity	0Krad	6Krad	10Krad	15Krad	25Krad	40Krad
A1	150 pA	500 pA	100 pA	0.00 A	250 pA	100 pA
A2	0.00 A	0.00 A	350 pA	200 pA	-800 pA	0.00 A
A3	-600 pA	-100 pA	-600 pA	300 pA	0.00 A	300 pA
A4	200 pA	50.0pA	0.00 A	-850 pA	0.00 A	0.00 A
B1	100 pA	0.00 A	-200 pA	450 pA	-300 pA	50.0pA
B2	-100 pA	0.00 A	300 pA	0.00 A	250 pA	0.00 A
B3	0.00 A	-550 pA	0.00 A	0.00 A	0.00 A	0.00 A
B4	-400 pA	50.0pA	0.00 A	250 pA	350 pA	400 pA

I_{in}

Pin Identity	0Krad	6Krad	10Krad	15Krad	25Krad	40Krad
A1	0.00 A	0.00 A	0.00 A	50.0pA	-550 pA	50.0pA
A2	-200 pA	100 pA	0.00 A	-550 pA	200 pA	50.0pA
A3	100 pA	0.00 A	0.00 A	-200 pA	0.00 A	100 pA
A4	0.00 A	200 pA	0.00 A	600 pA	100 pA	500 pA
B1	400 pA	250 pA	0.00 A	-400 pA	50.0pA	0.00 A
B2	0.00 A	0.00 A	-150 pA	0.00 A	-50.0pA	150 pA
B3	-400 pA	-200 pA	0.00 A	0.00 A	250 pA	0.00 A
B4	50.0pA	-100 pA	150 pA	0.00 A	0.00 A	-50.0pA

Input Leakage Current

Device Number 21 (Irradiated with bias)

Pin Number	I_{IH}				
	0Krad	6Krad	10Krad	15Krad	25Krad
A1	750 pA	750 pA	750 pA	1.55nA	1.15nA
A2	1.40nA	1.60nA	1.00nA	1.15nA	1.40nA
A3	600 pA	750 pA	1.00nA	50.0pA	750 pA
A4	350 pA	1.15nA	500 pA	350 pA	750 pA
B1	800 pA	400 pA	800 pA	600 pA	900 pA
B2	900 pA	800 pA	1.15nA	1.10nA	400 pA
B3	800 pA	50.0pA	1.20nA	500 pA	1.00nA
B4	800 pA	750 pA	1.20nA	800 pA	0.00 A

Pin Identity	I_{IH}				
	0Krad	6Krad	10Krad	15Krad	25Krad
A1	1.55nA	900 pA	800 pA	1.60nA	750 pA
A2	350 pA	200 pA	250 pA	150 pA	800 pA
A3	700 pA	1.35nA	350 pA	800 pA	750 pA
A4	0.00 A	0.00 A	350 pA	-400 pA	750 pA
B1	700 pA	550 pA	750 pA	300 pA	800 pA
B2	500 pA	-200 pA	150 pA	150 pA	1.00nA
B3	400 pA	650 pA	750 pA	800 pA	50.0pA
B4	-150 pA	50.0pA	50.0pA	0.00 A	800 pA

Pin Number	I_{IH}	
	40Krad	40Krad Annealed
A1	1.60nA	800 pA
A2	800 pA	1.35nA
A3	1.20nA	50.0pA
A4	1.60nA	1.60nA
B1	800 pA	1.20nA
B2	350 pA	1.60nA
B3	200 pA	500 pA
B4	750 pA	1.20nA

Pin Identity	I_{IH}	
	40Krad	40Krad Annealed
A1	1.00nA	1.80nA
A2	600 pA	250 pA
A3	750 pA	750 pA
A4	-50.0pA	1.00nA
B1	950 pA	800 pA
B2	0.00 A	50.0pA
B3	750 pA	350 pA
B4	300 pA	150 pA

Input Leakage Current

Device Number 32 (Irradiated with all pins grounded)

Pin Identity	I_{INL}				
	0Krad	6Krad	10Krad	15Krad	25Krad
A1	800 pA	1.75nA	350 pA	350 pA	1.60nA
A2	1.20nA	800 pA	750 pA	750 pA	750 pA
A3	800 pA	1.00nA	800 pA	800 pA	900 pA
A4	1.25nA	1.20nA	650 pA	650 pA	800 pA
B1	0.00 A	1.15nA	350 pA	350 pA	1.15nA
B2	350 pA	250 pA	950 pA	950 pA	550 pA
B3	350 pA	1.05nA	650 pA	650 pA	750 pA
B4	350 pA	350 pA	900 pA	900 pA	-100 pA
I_{INH}					
A1	1.60nA	650 pA	750 pA	750 pA	1.00nA
A2	150 pA	1.05nA	150 pA	150 pA	250 pA
A3	950 pA	350 pA	1.20nA	1.20nA	800 pA
A4	350 pA	1.20nA	50.0pA	50.0pA	650 pA
B1	550 pA	350 pA	800 pA	800 pA	800 pA
B2	350 pA	350 pA	0.00 A	0.00 A	1.40nA
B3	100 pA	750 pA	150 pA	150 pA	1.05nA
B4	200 pA	750 pA	0.00 A	0.00 A	800 pA

Input Leakage Current

Device Number 73 (Control-not irradiated)

Pin Identity	I_{in}			
	0Krad	6Krad	10Krad	15Krad
A1	950 pA	800 pA	2.30nA	1.60nA
A2	800 pA	900 pA	550 pA	800 pA
A3	1.10nA	1.00nA	1.45nA	150 pA
A4	100 pA	750 pA	800 pA	350 pA
B1	900 pA	150 pA	1.40nA	800 pA
B2	250 pA	1.00nA	350 pA	350 pA
B3	550 pA	1.00nA	600 pA	450 pA
B4	500 pA	750 pA	100 pA	250 pA
			25Krad	40Krad
			1.40nA	1.60nA
			1.55nA	650 pA
			550 pA	1.60nA
			900 pA	800 pA
			1.00nA	750 pA
			800 pA	1.30nA
			50.0pA	750 pA
			1.50nA	800 pA

Pin Identity	I_{in}			
	1.50nA	1.20nA	1.20nA	900 pA
A1	1.50nA	1.20nA	1.25nA	900 pA
A2	600 pA	100 pA	1.20nA	350 pA
A3	1.05nA	1.20nA	1.20nA	1.05nA
A4	350 pA	150 pA	800 pA	300 pA
B1	150 pA	350 pA	600 pA	550 pA
B2	950 pA	400 pA	1.15nA	650 pA
B3	150 pA	800 pA	0.00 A	800 pA
B4	1.30nA	400 pA	1.00nA	250 pA
			500 pA	400 pA
			150 pA	1.00nA
			550 pA	400 pA
			800 pA	550 pA
			650 pA	-100 pA
			250 pA	150 pA
			550 pA	0.00 A
			550 pA	150 pA

Quiescent Device Current

V_{cc}: 6.0V

Device
Number

0Krad 6Krad 10Krad 15Krad 25Krad 40Krad 40Krad
Annealed

QUIESCENT CURRENT - ALL INPUTS HIGH LIMIT : 1.00μA

21	12.80nA	1.840μA	9.950μA	42.00μA	111.5μA	296.0μA	54.00μA
22	6.850nA	3.675μA	19.25μA	71.50μA	191.5μA	402.0μA	63.50μA
23	4.750nA	2.555μA	17.60μA	63.50μA	184.0μA	400.0μA	96.00μA
24	6.300nA	2.680μA	14.55μA	72.00μA	151.5μA	324.5μA	63.50μA

QUIESCENT CURRENT - ALL INPUTS LOW LIMIT : 1.00μA

21	6.400nA	44.75nA	955.0nA	17.20μA	88.00μA	195.5μA	35.20μA
22	12.75nA	122.5nA	3.515μA	38.55μA	127.0μA	272.0μA	51.10μA
23	-3.20nA	111.5nA	2.555μA	33.40μA	107.5μA	283.5μA	61.60μA
24	6.400nA	83.50nA	2.230μA	28.20μA	95.50μA	248.0μA	56.00μA

QUIESCENT CURRENT - ALL INPUTS HIGH LIMIT : 1.00μA

32	6.350nA	3.950nA	3.10nA	0.000 A	6.40nA	6.350nA
H7	2.350nA	4.750nA	3.150nA	-9.650nA	9.60nA	6.400nA
H8	6.750nA	6.400nA	6.400nA	7.200nA	6.400nA	-9.800nA
H9	6.350nA	-6.400nA	-6.900nA	-8.650nA	6.300nA	5.550nA

QUIESCENT CURRENT - ALL INPUTS LOW LIMIT : 1.00μA

32	12.70nA	-4.250nA	-6.40nA	6.400nA	-9.65nA	3.150nA
H7	7.20nA	7.150nA	6.350nA	9.300nA	-6.00nA	12.70nA
H8	-12.50nA	-9.600nA	6.550nA	5.200nA	-3.20nA	3.150nA
H9	10.00nA	6.350nA	9.200nA	6.350nA	6.35nA	2.350nA

THRESHOLD VOLTAGE N-CHANNEL: -450 mV <---> -1.45 V

Device Number	0Krad	6Krad	10Krad	15Krad	25Krad	40Krad	40Krad Annealed
21	-1.17 V	-1.17 V	-1.16 V	-1.15 V	-1.20 V	-1.30 V	-1.15 V
32	-1.17 V	-1.17 V	-1.16 V	-1.15 V	-1.13 V	-1.15 V	
73	-1.21 V	-1.20 V	-1.18 V	-1.19 V	-1.19 V	-1.17 V	

THRESHOLD VOLTAGE P-CHANNEL: 450 mV <---> 1.35 V

Device Number	0Krad	6Krad	10Krad	15Krad	25Krad	40Krad	40Krad Annealed
21	468 mV	523 mV	-440 mV	-680 mV	-725 mV	-755 mV	-690 mV
32	470 mV	530 mV	563 mV	601 mV	665 mV	750 mV	
73	483 mV	485 mV	481 mV	482 mV	479 mV	483 mV	

Output Voltage

Device Number 21

V_{CC} : 4.5 V
 I_{OHL} : 20 μ A
 I_{OHL} : -20 μ A
 I_{OIL2} : 4.0mA
 I_{OHL2} : -4.0mA

Pin Identity	0Krad	6Krad	10Krad	15Krad	25Krad	40Krad	40Krad Annealed
V _{OIL1} Y1	2.35mV	2.25mV	2.20mV	2.50mV	2.30mV	2.70mV	2.35mV
Y2	2.35mV	2.20mV	2.25mV	2.35mV	2.20mV	2.65mV	2.40mV
Y3	2.20mV	2.25mV	2.15mV	2.40mV	2.25mV	2.60mV	2.35mV
Y4	2.20mV	2.15mV	2.20mV	2.35mV	2.25mV	2.35mV	2.25mV
V _{OHL} Y1	4.50 V	4.50 V	4.50 V	4.49 V	4.49 V	4.49 V	4.49 V
Y2	4.49 V	4.49 V	4.50 V	4.49 V	4.49 V	4.49 V	4.50 V
Y3	4.50 V	4.49 V	4.50 V				
Y4	4.50 V	4.49 V	4.50 V	4.49 V	4.49 V	4.49 V	4.49 V
V _{OIL2} Y1	122 mV	125 mV	120 mV	122 mV	115 mV	118 mV	117 mV
Y2	119 mV	122 mV	118 mV	118 mV	113 mV	116 mV	116 mV
Y3	120 mV	122 mV	118 mV	118 mV	113 mV	116 mV	114 mV
Y4	118 mV	121 mV	115 mV	116 mV	112 mV	114 mV	113 mV
V _{OHL2} Y1	4.38 V	4.37 V	4.38 V				
Y2	4.38 V	4.37 V	4.37 V				
Y3	4.38 V						
Y4	4.38 V	4.38 V	4.38 V	4.38 V	4.37 V	4.36 V	4.36 V

Output Voltage

Device Number 32

V_{CC} : 6.0 V
 I_{OL1} : 20 μ A
 I_{OH1} : -20 μ A
 I_{OL2} : 5.2mA
 I_{OH2} : -5.2mA

Pin Identity	0Krad	6Krad	10Krad	15Krad	25Krad	40Krad
V _{OL1} Y1	1.80mV	2.25mV	1.85mV	2.00mV	2.00mV	2.25mV
Y2	1.75mV	2.20mV	1.85mV	2.00mV	2.00mV	2.20mV
Y3	1.95mV	2.20mV	1.95mV	1.95mV	1.95mV	2.35mV
Y4	1.80mV	2.20mV	1.80mV	1.95mV	2.00mV	2.25mV
V _{OH1} Y1	5.99 V					
Y2	5.99 V					
Y3	5.99 V					
Y4	5.99 V					
V _{OL2} Y1	117 mV	122 mV	120 mV	116 mV	117 mV	113 mV
Y2	115 mV	119 mV	116 mV	114 mV	113 mV	110 mV
Y3	116 mV	119 mV	116 mV	112 mV	114 mV	110 mV
Y4	113 mV	116 mV	115 mV	111 mV	113 mV	109 mV
V _{OH2} Y1	5.87 V					
Y2	5.86 V					
Y3	5.87 V					
Y4	5.87 V	5.86 V	5.87 V	5.86 V	5.86 V	5.86 V

Quiescent Device Current v Total Dose

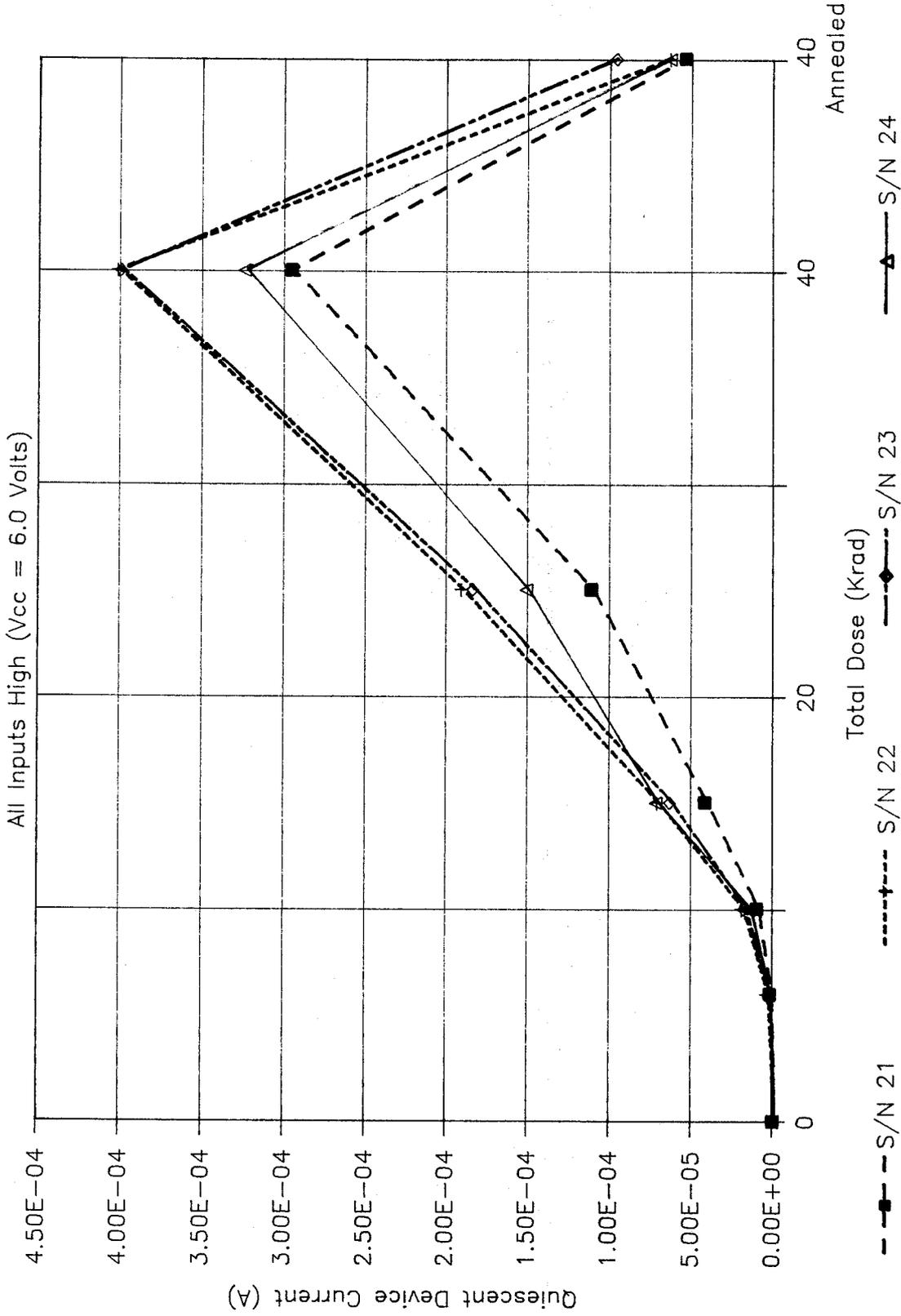


Figure 2

Quiescent Device Current v Total Dose

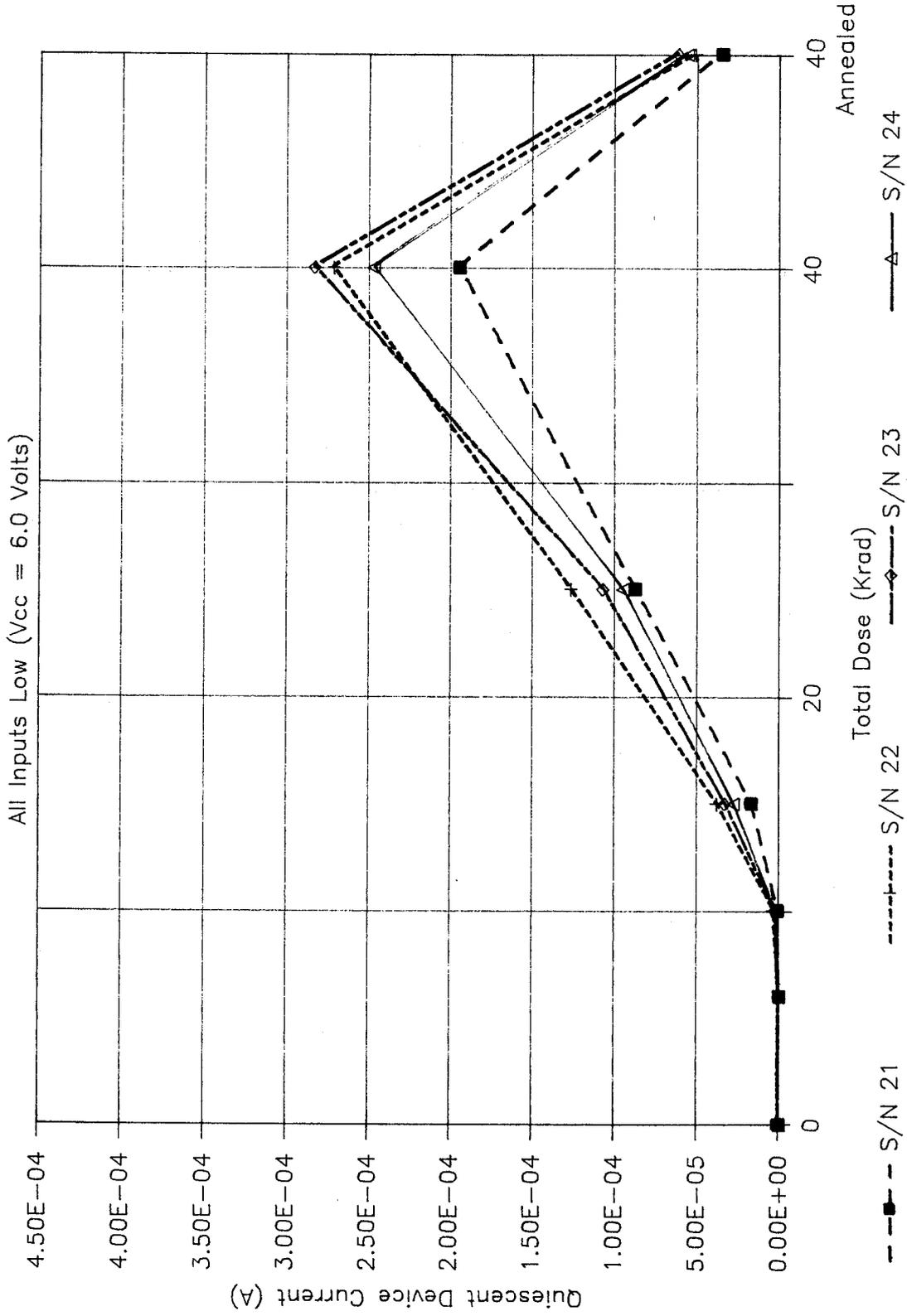


Figure 3

Threshold Voltage v Total Dose

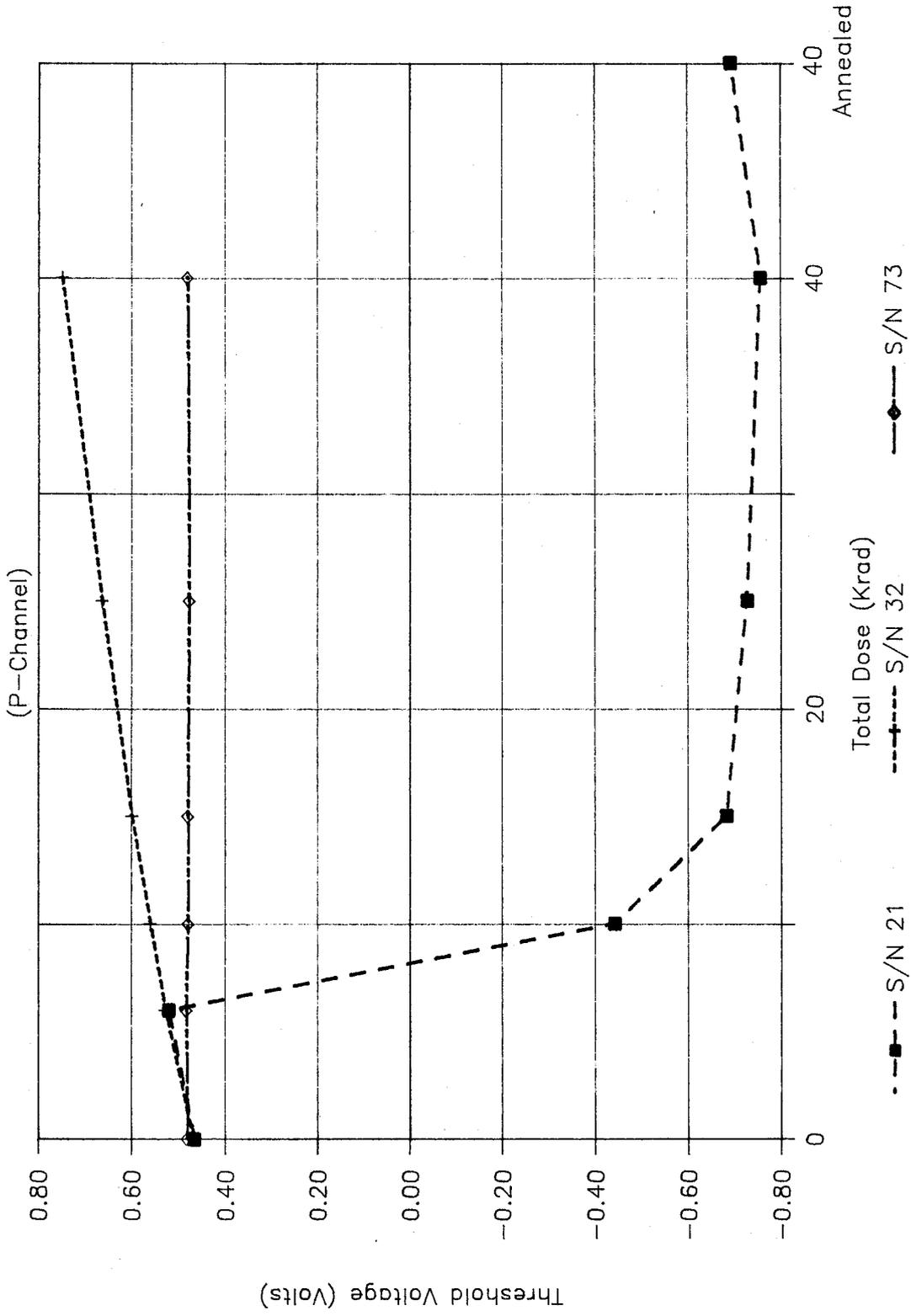


Figure 4